

RTC-700M

Environment Test Report

Report NO: 16R020001

Summary	<p><input checked="" type="checkbox"/> Pass</p> <p><input type="checkbox"/> Fail</p> <p>Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input type="checkbox"/> Pass with Deviation</p> <p>Comment: _____</p>
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Issue date

2016-05-11

QE Manager

KJ Wang

Test Engineer

Ben Sun

Test Item List

1. <i>Test Item List</i> -----	2
2. <i>Test Configuration</i> -----	3
3. <i>Room Temperature Test</i> -----	4
4. <i>Temperature Rise Test</i> -----	7
5. <i>High Temperature Storage Test</i> -----	10
6. <i>High Temperature Operation Test</i> -----	11
7. <i>Low Temperature Storage Test</i> -----	12
8. <i>Low Temperature Operation Test</i> -----	13
9. <i>Humidity Test</i> -----	14
10. <i>Temperature Shock Operation Test</i> -----	15
11. <i>Temperature Shock Non-operation Test</i> -----	16
12. <i>Cold Start And Hot Start Test</i> -----	17

Testing Result

Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	
2	Room temperature test	Pass	
3	Temperature rise test	Pass	
4	High temperature storage test	Pass	
5	High temperature operation test	Pass	
6	Low temperature storage test	Pass	
7	Low temperature operation test	Pass	
8	Humidity test	Pass	
9	Temperature shock operation test	Pass	
10	Temperature shock non-operation test	Pass	
11	Cold start and hot start test	Pass	

Configuration of EUT

Test Product: RTC-700M		
Sample Configuration & Quantity Under Test:		
Num	Item	Description
RTC-700M		
01.	CPU:	TI OMAP 4470
02.	PCBA	A0.3_0_1
03.	BIOS	none
04.	Memory	1GB LPDDR2 + 16GB eMMC
05.	Storage	16GB eMMC flash
06.	3G	QUECTEL UC20-G
07.	WLAN + BT Module	Jorjin WG7550 WIFI+BT_GPS module
08.	Battery	GETAC 2S1P 1530mAh x 2
09.	AC Adapter	FSP036-RBBN2
10.	Test Software	Android Stability Test APP

Room Temperature test

Test Date: 03-13-2016

Test Product: RTC-700M

Test Site: AAEON QE Dept.

Temperature Measurement:

40 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: DA100-13-1D
Date of Calibration: 09/10/15
Serial Number: 12A323190

Test Condition:

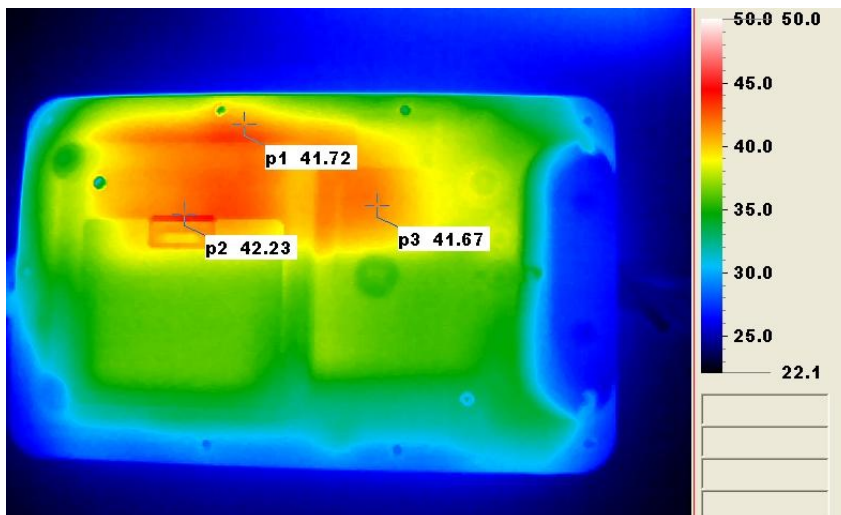
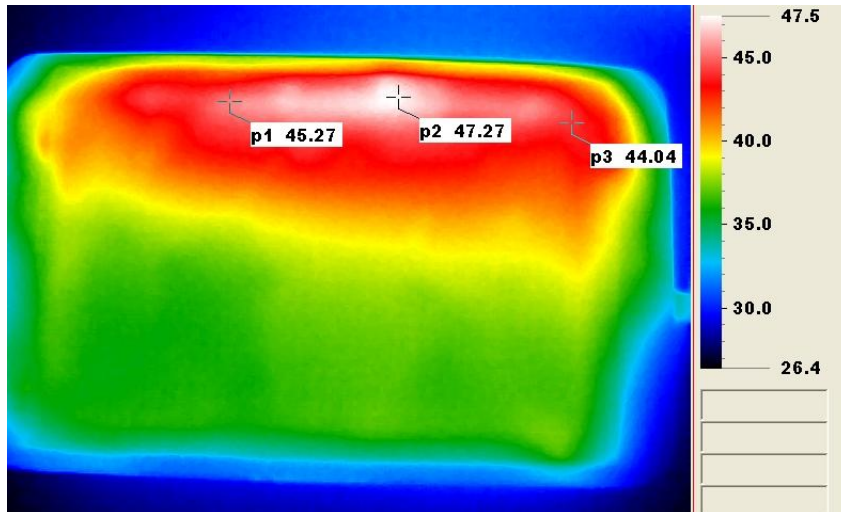
Ambient temperature: 25°C
Continuous running till temperature stable (within less than 1°C)

Test Software:

Android 4.2.2 / Run Stability Test App

Terminal Recorder:

Measuring Thermal Couple Position :



Room Temperature test



Thermal profile data:**RTC-700M**

Point	Temp. Stage(°C)	Spec	25
1. Point 1		ΔT ≤ 25 °C	44.6
2. Point 2			44.5
3. Point 3			44.7
4. Point 4			43.8
5. Point 5			47.3
6. Point 6 -			44.7
Room Temperature			24.9
Any Tm value showed in red words which meaning the value over the Tc degree Cof this device specification.			

Sample Configuration & Quantity Under Test:

Quantity: 1 (RTC-700M)

Test Result:

No issues were found during the room temperature operation test.

Temperature rise test

Test Date: 03-08~10-2016

Test Product: RTC-700M

Test Site: AAEON QE Dept.

Test Standard: Refer to EN 61131-2(94), UL508 (94)

Temperature Measurement:

40 Channel Thermal Recorder:

YOKOGAWA Inc,

Model: DA100-13-1D

Date of Calibration: 09/10/15

Serial Number: 12A323190

Test Condition:

Ambient temperature: 35°C

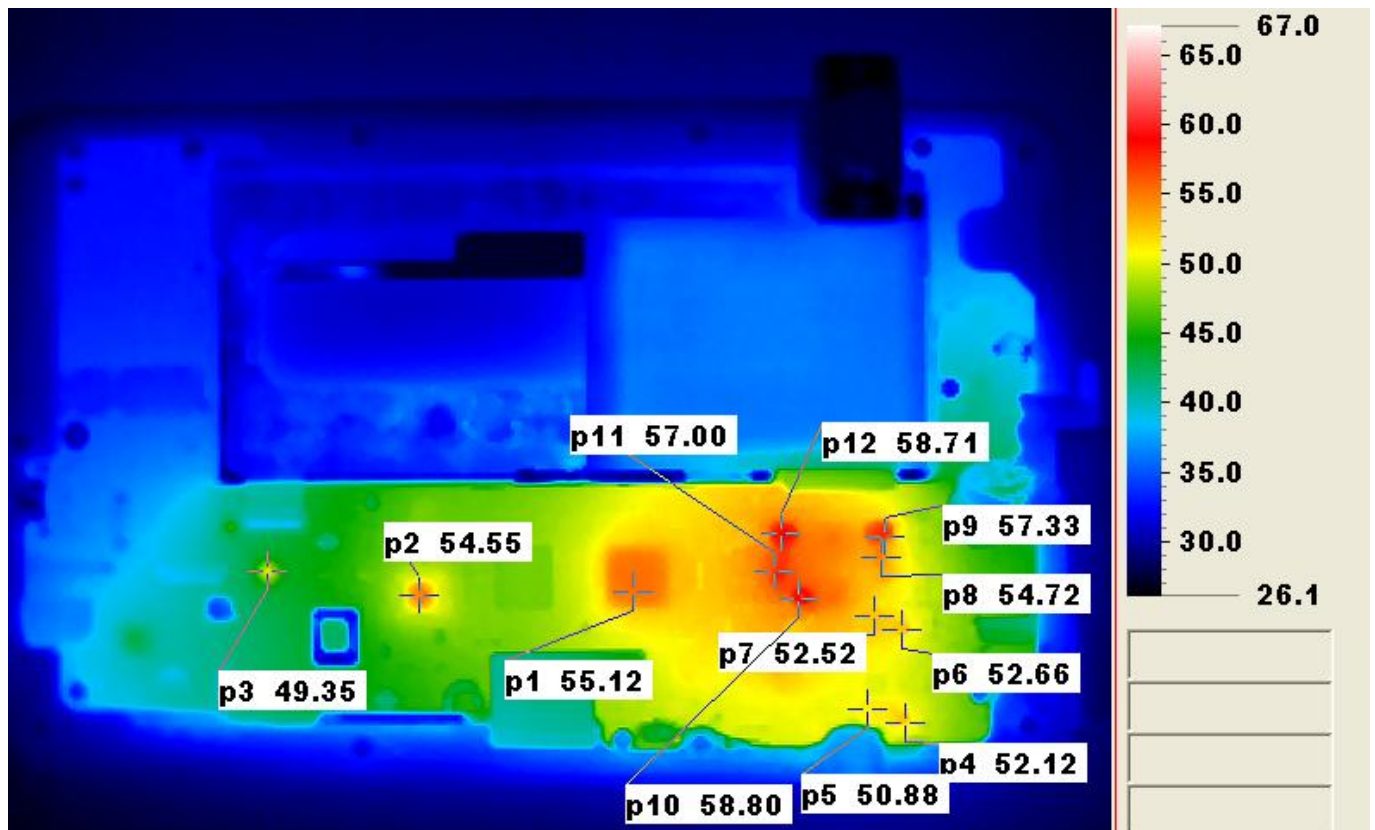
Continuous running till thermal stability (within less than 1°C)

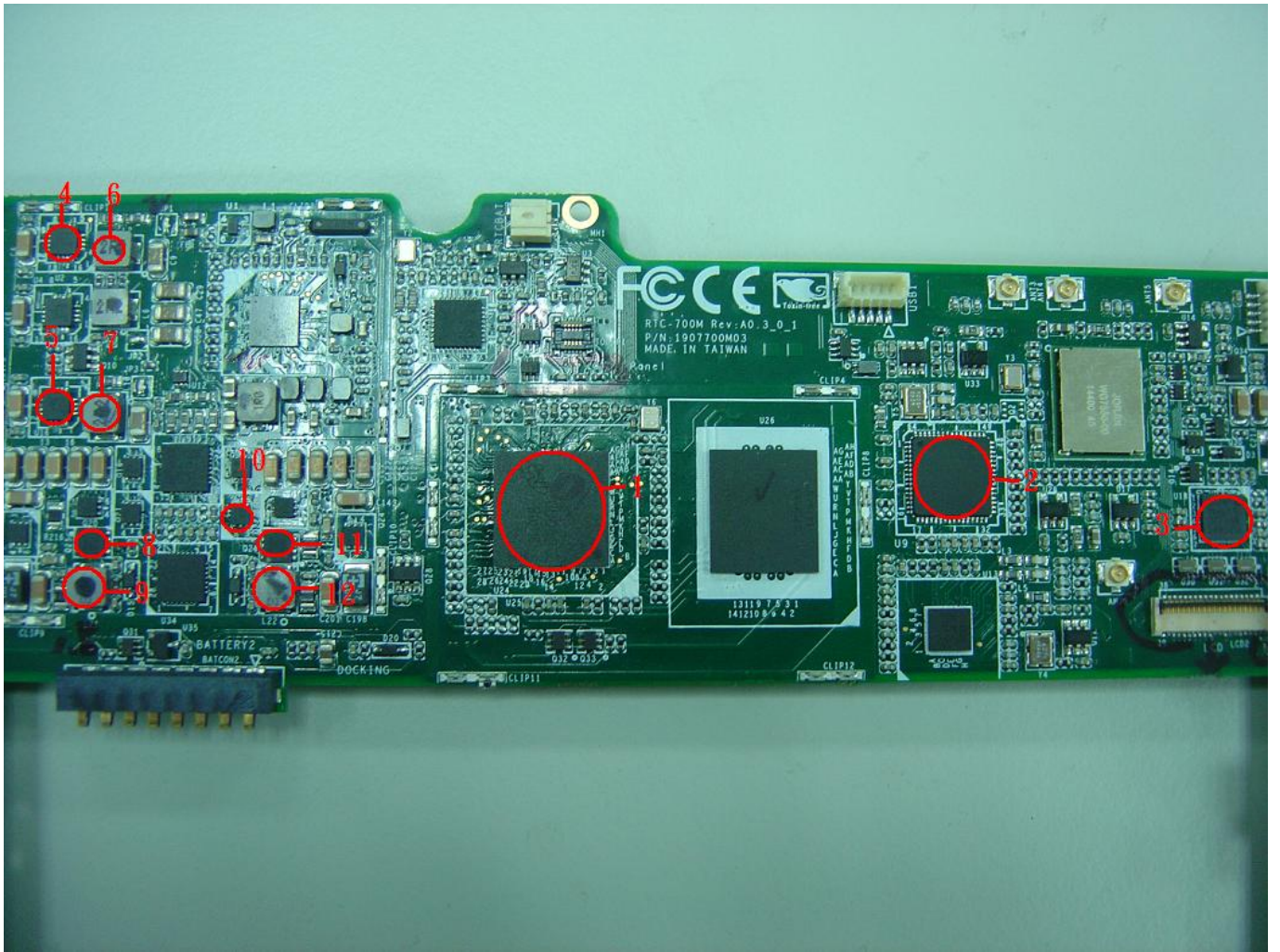
Test Software:

Android 4.2.2 / Run Stability Test App

Terminal Recorder:

Measuring Thermal Couple Position :





Thermal profile data:

RTC-700M

Point	Position	Describe	Tc (*1) (°C)	Tm (*2) Measured Under	Note
				35.0°C	
1	U25	(TF)TI CPU.OMAP4470.1.5GHz.PBGA 547P.SMD.44705GPCBS	100	75.0	
2	U9	(TF)IC.USB2.0 7-PORT HUB CONTROLLER.QFN 64.SMD.SMSC USB2517i-JZX	100	68.0	
3	U18	(TF)IC.DSI2LVDS Bridge.BGA 49P.SMD.Toshiba.TC358764XBG	100	61.8	
4	U2	(TF)IC.Step-Down Converter.2.5MHz.QFN-16.SMD TI TPS62130RGT	100	68.6	
5	U16	(TF)IC.Step-Down Converter.2.5MHz QFN-16.SMD TI TPS62130RGT	100	66.7	
6	L2	(TF)COIL.2.2uH.DCR=52mohm.Idc=3Amp.20%.SMD.4.45*4.05* 2.0mm.Zenithtek.ZPWM-4020M-2R2M	150	67.3	
7	L18	(TF)COIL.2.2uH.DCR=52mohm.Idc=3Amp.20%.SMD.4.45*4.05* 2.0mm.Zenithtek.ZPWM-4020M-2R2M	150	63.0	
8	Q23	(TF)PWR.Dual P-Channel MOSFET.Vds=-30V.Vgs=±25V Id=-3.3A SMD.FAIRCHILD.FDMA3027PZ	150	62.0	
9	L21	(TF)COIL.8.2uH.DCR=188mΩ.Irms=1.8Amp.20%.SMD.4.5*4.0*1 .8mm.GOTREND.GSTD4020PM-8R2M	150	66.8	
10	Q22	(TF)PWR.Dual P-Channel MOSFET.Vds=-30V Vgs=±25V Id=-3.3A SMD FAIRCHILD.FDMA3027PZ	150	66.6	
11	Q24	(TF)PWR.Dual P-Channel MOSFET.Vds=-30V Vgs=±25V Id=-3.3A.SMD.FAIRCHILD.FDMA3027PZ	150	66.4	
12	L22	(TF)COIL.8.2uH.DCR=188mΩ.Irms=1.8Amp.20%.SMD.4.5*4.0*1 .8mm.GOTREND.GSTD4020PM-8R2M	150	43.5	
13		System Ta (Inside)		38.6	

Note(*):

1. "Tc" indicates the component's case maximum temperature value specified in its datasheet.
2. "TAT" indicates the actual measured temperature in chamber.
3. "TPT" indicates the predicted temperature by offset from TAT

4. Judgment Criteria:

- **Fail** : Tm > Tc; The measured value is over specification.
- **Margin Pass** : Tc > Tm > Tc-5°C; The measured value is within specification with margin.
It is strongly recommended to add thermal dissipation design for better reliability.
- **Pass** : Tm < Tc-5°C; The measured value is with safety margin.

5. Defect NO.

Sample Configuration & Quantity Under Test:

Quantity: 1 (RTC-700M)

Test Result:

No issues were found during the temperature rise operation test.

High temperature storage test

Test Date: 02-15 ~ 21-2016

Test Product: RTC-700M

Test Site: AAEON QE Dept.

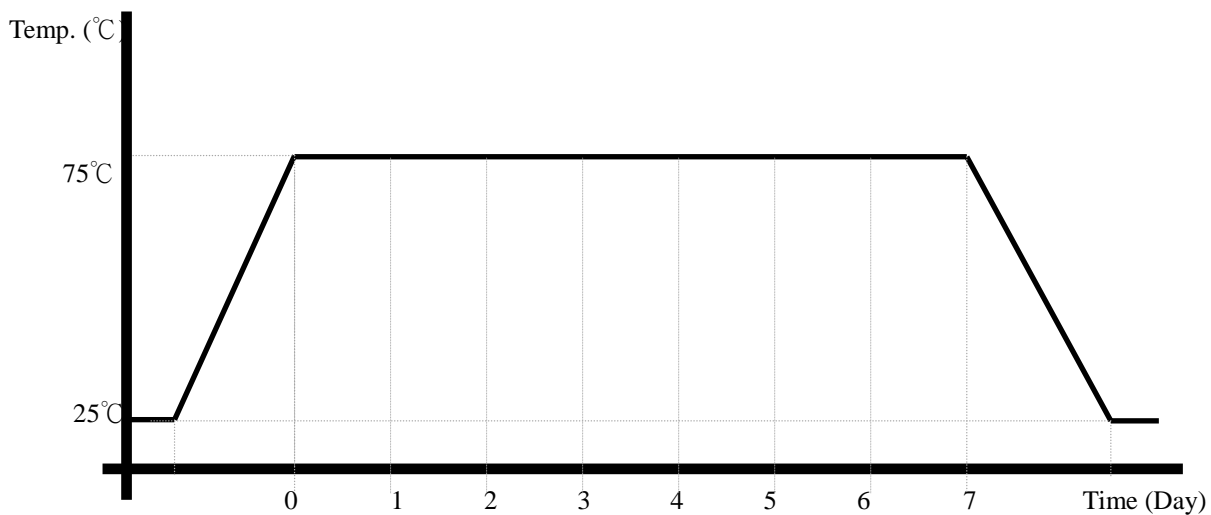
Test Standard: Refer to MIL-STD 810G Method 501.5 High Temperature
Procedure I - Storage

Test Equipment:

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)
Model: THS-B6T-150+LN2
Date of Calibration: 06/05/15
Serial Number: 9095KT

Testing Item:

1. Test Temperature: 75°C
2. Test Time: 7days
3. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (RTC-700M)

Test Result:

No issues were found after the high temperature storage test.

High temperature operation test

Test Date: 02-04 ~ 09-2016

Test Product: RTC-700M

Test Site: AAEON QE Dept.

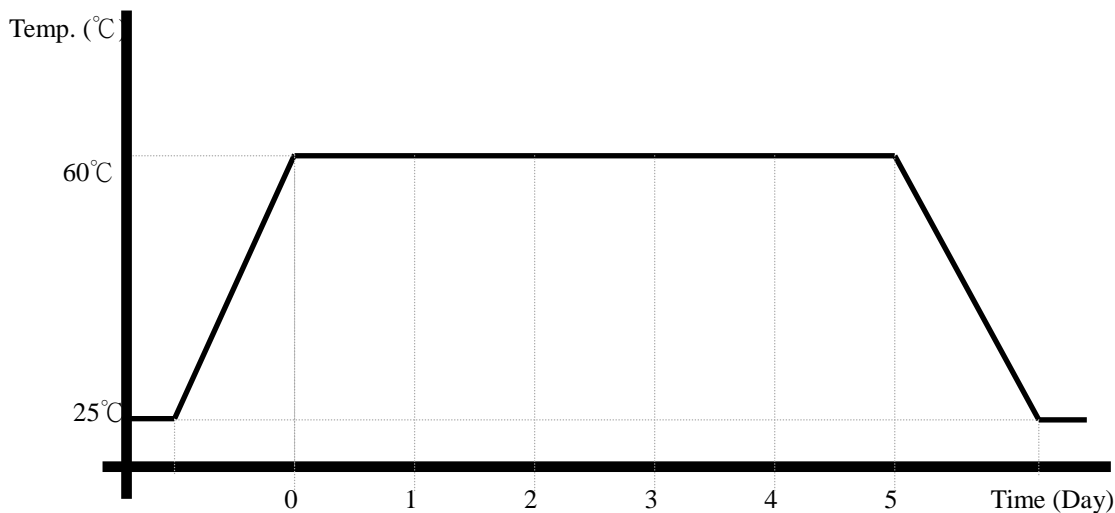
Test Standard: Refer to MIL-STD 810G Method 501.5 High Temperature
Procedure II - Operation

Test Equipment:

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)
Model: THS-B6T-150+LN2
Date of Calibration: 06/05/15
Serial Number: 9095KT

Testing Item:

1. Test Temperature: 60°C
2. Test Time: 5days
3. Test Software: Android 4.2.2 / Run Stability Test App
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (RTC-700M)

Test Result:

No issues were found during the high temperature operation test.

Low temperature storage test

Test Date: 02-03~04-2016

Test Product: RTC-700M

Test Site: AAEON QE Dept.

Test Standard: Refer to MIL-STD 810G Method 502.5 Low Temperature
Procedure I - Storage

Test Equipment:

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)

Model: THS-B6T-150+LN2

Date of Calibration: 06/05/15

Serial Number: 9095KT

Testing Item:

1. Test Temperature: -55°C
2. Test Times: 24Hrs
3. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (RTC-700M)

Test Result:

No issues were found after the low temperature storage test.

Low temperature operation test

Test Date: 02-02~03-2016

Test Product: RTC-700M

Test Site: AAEON QE Dept.

Test Standard: Refer to MIL-STD 810G Method 502.5 High Temperature
Procedure II - Operation

Test Equipment:

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)

Model: THS-B6T-150+LN2

Date of Calibration: 06/05/15

Serial Number: 9095KT

Testing Item:

1. Test Temperature: -23°C
2. Test Times: 24Hrs
3. Test Software: Android 4.2.2 / Run Stability Test App
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (RTC-700M)

Test Result:

No issues were found during the low temperature operation test.

Humidity test

Test Date: 05-09~11-2016

Test Product: RTC-700M

Test Site: AAEON QE Dept.

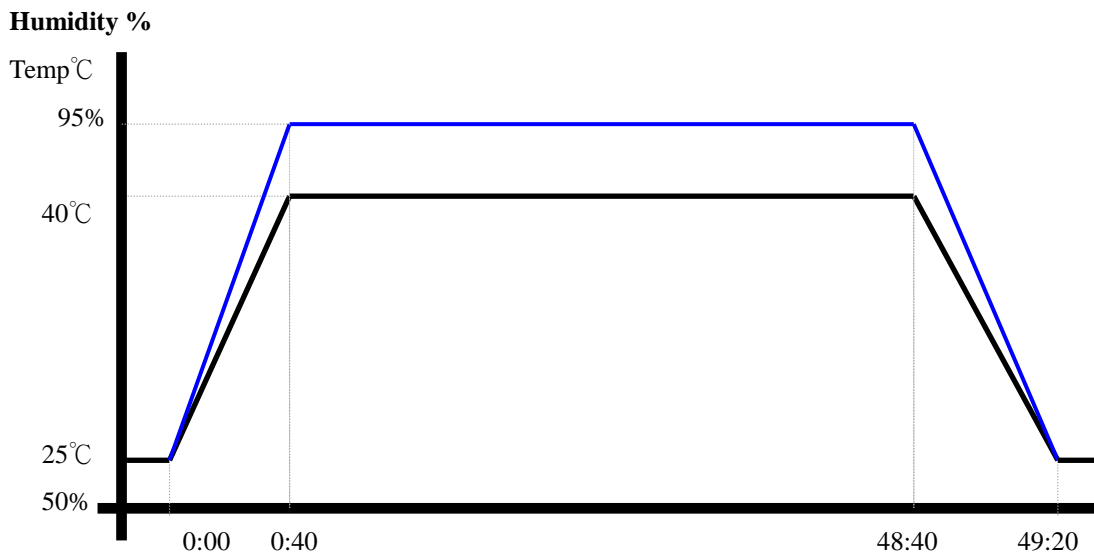
Test Standard: Refer to IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)
Model: THS-B6T-150+LN2
Date of Calibration: 06/05/15
Serial Number: 9095KT

Testing Item:

1. Test Temperature: 40°C
2. Test Humidity: 95% RH
3. Test Times: 48Hrs
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (RTC-700M)

Test Result:

No issue was found after the humidity storage test.

Temperature shock operation test

Test Date: 03-02~03-2016

Test Product: RTC-700M

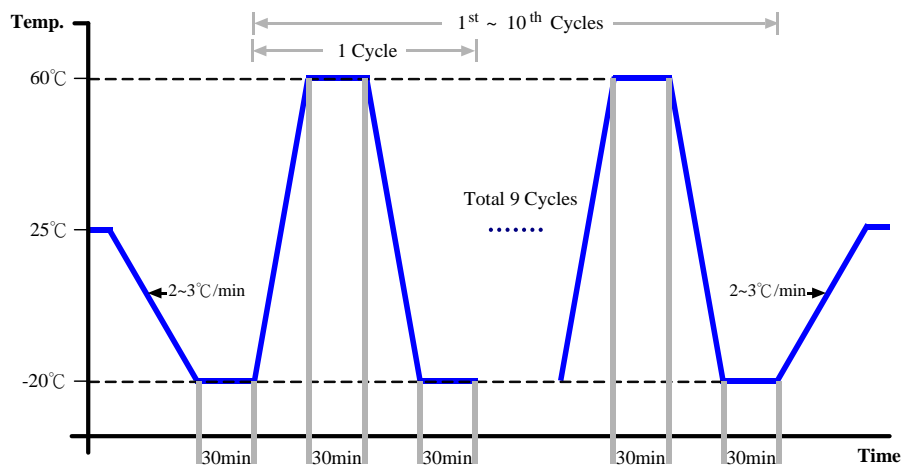
Test Site: AAEON QE Dept.

Test Standard: Refer to MIL-STD 810G Method 503.5 Temperature Shock
Procedure I - Shock from constant extreme temperatures

Test Equipment:
Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)
Model: THS-B6T-150+LN2
Date of Calibration: 06/05/15
Serial Number: 9095KT

Test Condition:

1. Test Low Temperature: -20°C
2. Test High Temperature: 60°C
3. Test dwell time: 30min
4. Temperature slope: 5 min
5. Test cycle: 10 cycles
6. Test Software: Android 4.2.2 / Run Stability Test App
7. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (RTC-700M)

Test Result:

No issues were found during the variation temperature operation test.

Temperature shock non-operation test

Test Date: 03-03~05-2016

Test Product: RTC-700M

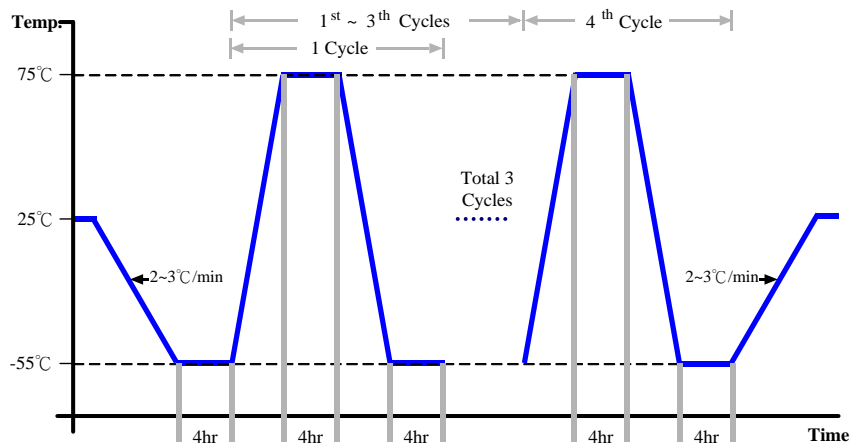
Test Site: AAEON QE Dept.

Test Standard: Refer to MIL-STD 810G Method 503.5 Temperature Shock
Procedure I - Shock from constant extreme temperatures

Test Equipment:
Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)
Model: THS-B6T-150+LN2
Date of Calibration: 06/05/15
Serial Number: 9095KT

Test Condition:

1. Test Low Temperature: -55°C
2. Test High Temperature: 75°C
3. Test dwell time: 4Hrs
4. Temperature slope: 10 min
5. Test cycle: 4 cycles
6. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (RTC-700M)

Test Result:

No issues were found after the variation temperature non-operation test.

Cold start and hot start test

Test Date: 02-01~02-2016

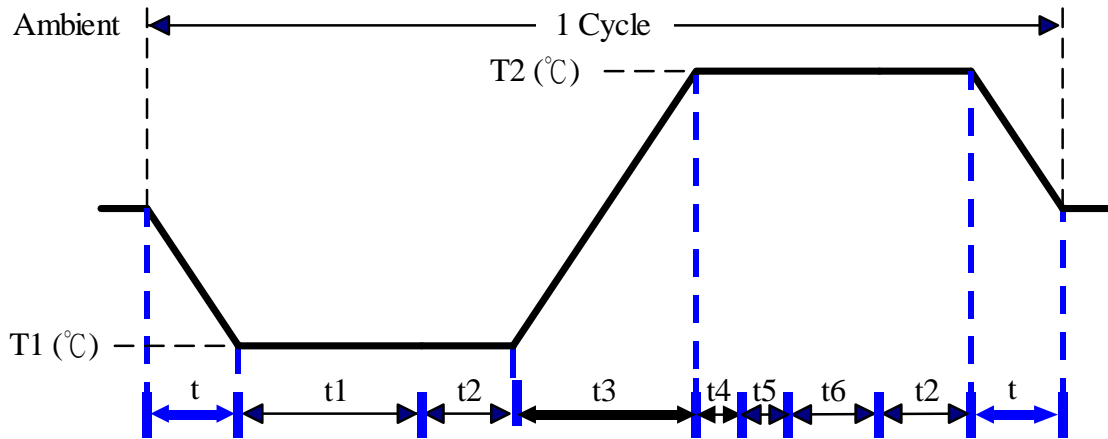
Test Product: RTC-700M

Test Site: AAEON QE Dept.

Test Standard: Refer to IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:
Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP).
Model: THS-B6T-150+LN2
Date of Calibration: 06/05/15
Serial Number: 9095KT

Test Condition:



Parameters	Description
T1	-5°C
T2	45°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope
t , t1, t6: Power Off
t2: Power on/off test 10 times (on 2 min / off 5min)
t3, t4: Stability Test
t5: Android Software restart test 3 times
Test Software:Android 4.2.2

Test Result:

- a. No issues were found during the cold start test.
- b. No issues were found during the hot start test.